SiC JFET Division

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Silicon Carbide (SiC) Cascode JFET -EliteSiC, Power N-Channel, TOLL, 750V, 58 mohm

Rev. D, January 2025

Description

The UJ4C075060L8S is a 750V, 58mΩ G4 SiC FET. It is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows use of off-the-shelf gate drivers hence requiring minimal re-design when replacing Si IGBTs, Si superjunction devices or SiC MOSFETs. Available in the space-saving MO-229 package which enables automated assembly, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

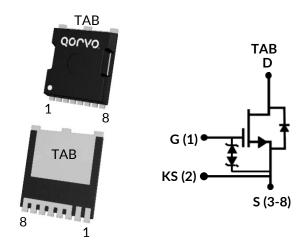
- On-resistance $R_{DS(on)}$: 58m Ω (typ)
- Operating temperature: 175°C (max)
- Excellent reverse recovery: Q_{rr} = 70nC
- Low body diode V_{FSD}: 1.31V
- Low gate charge: Q_G = 37.8nC
- Threshold voltage V_{G(th)}: 4.8V (typ) allowing 0 to 15V drive
- Low intrinsic capacitance
- ESD protected, HBM class 2
- MO-229 package for faster switching, clean gate waveforms

Typical applications

- Line rectification and active-bridge rectification circuits in AC/DC front-ends
- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating

DATASHEET

UJ4C075060L8S



Part Number	Package	Marking
UJ4C075060L8S	MO-229	UJ4C075060







Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V _{DS}		750	V
Gate-source voltage	V _{GS}	DC	-20 to +20	V
	V GS	AC (f > 1Hz)	-25 to +25	V
Continuous drain current ¹		T _C = 25°C	27.8	А
	ID	T _C = 100°C	20.6	А
Pulsed drain current ²	I _{DM}	T _C = 25°C	82	А
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =1.8A	24.3	mJ
SiC FET dv/dt ruggedness	dv/dt	$V_{DS} \le 500V$	200	V/ns
Power dissipation	P _{tot}	T _C = 25°C	155	W
Maximum junction temperature	T _{J,max}		175	°C
Operating and storage temperature	TJ, T _{STG}		-55 to 175	°C
Reflow soldering temperature	T _{solder}	reflow MSL 1	260	°C

1. Limited by $T_{J,max}$

2. Pulse width t_p limited by $T_{J,max}$

3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol Test Co	Test Conditions		Units		
Parameter		Test Conditions	Min	Тур	Max	OTILS
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.75	0.97	°C/W



Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Cumhal	Test Conditions		1.1		
Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Drain-source breakdown voltage	BV _{DS}	V _{GS} =0V, I _D =1mA	750			V
Total drain leakage current		V _{DS} =750V,		0.7	40	
		V _{GS} =0V, T _J =25°C		0.7	40	μA
	I _{DSS}	V _{DS} =750V,		15		μΑ
		V _{GS} =0V, T _J =175°C		15		
Total gate leakage current	1	V _{DS} =0V, T _J =25°C,	4.7	20		
	I _{GSS}	V _{GS} =-20V / +20V		4.7	20	μΑ
		V_{GS} =12V, I _D =20A,		58	74	
		TJ=25°C				
Drein course on registeries		V_{GS} =12V, I _D =20A,		106		mΩ
Drain-source on-resistance	R _{DS(on)}	T_=125°C		100		
		V _{GS} =12V, I _D =20A,		4 4 7		
		т _ј =175°С		147	147	
Gate threshold voltage	V _{G(th)}	V _{DS} =5V, I _D =10mA	4	4.8	6	V
Gate resistance	R _G	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Units		
Faranteter	Symbol	Test Conditions	Min	Тур	Max	Onits
Diode continuous forward current ¹	I _S	T _C =25°C			27.8	Α
Diode pulse current ²	I _{S,pulse}	T _C =25°C			82	А
		V _{GS} =0V, I _S =10A,		1.01	1 75	
Converd veltage	V	T_=25°C		1.31	1.75	V
Forward voltage	V _{FSD}	V _{GS} =0V, I _S =10A,		1.0		V
		т _ј =175°С		1.8		
	0	V _{DS} =400V, I _S =20A,		66		
Reverse recovery charge	Q _{rr}	V_{GS} =0V, R_{G} =33 Ω ,		00		nC
Reverse recovery time	t _{rr}	di/dt=1400A/µs,		16		ns
	۲r	T_=25°C		10		
Reverse recovery charge	Q _{rr}	V_{DS} =400V, I _S =20A,		77		nC
	≺rr	V_{GS} =0V, R_{G} =33 Ω ,				
Reverse recovery time	+	di/dt=1400A/µs,		19		ns
	t _{rr}	T _J =150°C		1/		115





Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
Parameter	Symbol	Test Conditions –	Min	Тур	Max	Units
Input capacitance	C _{iss}	- V _{DS} =400V, V _{GS} =0V -		1420		
Output capacitance	C _{oss}	f=100kHz		41		pF
Reverse transfer capacitance	C _{rss}			2.7		
Effective output capacitance, energy	C	V_{DS} =0V to 400V,		50		pF
related	C _{oss(er)}	V _{GS} =0V		50		pi
Effective output capacitance, time	C	V _{DS} =0V to 400V,		0.4		
related	C _{oss(tr)}	V _{GS} =0V		94		pF
C _{OSS} stored energy	E _{oss}	V _{DS} =400V, V _{GS} =0V		4		μJ
Total gate charge	Q _G	V _{DS} =400V, I _D =20A,		37.8		
Gate-drain charge	Q_{GD}	$\frac{Q_{GD}}{Q_{GS}} \qquad \qquad V_{GS} = 0V \text{ to } 15V$		8		nC
Gate-source charge	Q_{GS}			11.8		
Turn-on delay time	t _{d(on)}	$\begin{tabular}{ c c c c } \hline Note 4, & & & \\ \hline V_{DS} = 400V, I_D = 20A, Gate & & \\ \hline Driver = 0V to +15V, & & \\ \hline Turn-on R_{G,EXT} = 1\Omega, & & \\ \hline Turn-off R_{G,EXT} = 33\Omega & & \\ \hline \end{tabular}$		10		- ns
Rise time	t _r			27		
Turn-off delay time	$t_{d(off)}$			96		
Fall time	t _f			11		
Turn-on energy	E _{ON}	Inductive Load, FWD: same device with		165		
Turn-off energy	E _{OFF}	$V_{GS} = 0V, R_G = 33\Omega,$		42		μJ
Total switching energy	E _{TOTAL}	TJ=22°C		207		
Turn-on delay time	t _{d(on)}	Note 4,		10		
Rise time	t _r	V_{DS} =400V, I_D =20A, Gate		30		nc nc
Turn-off delay time	$t_{d(off)}$	Driver =0V to +15V, Turn-on $R_{G,EXT}$ =1 Ω , Turn-off $R_{G,EXT}$ =33 Ω		100		– ns
Fall time	t _f			12		
Turn-on energy	E _{ON}	Inductive Load, FWD: same device with		181		
Turn-off energy	E _{OFF}	$V_{GS} = 0V, R_G = 33\Omega,$		47		μ
Total switching energy	E _{TOTAL}	T _J =150°C		228		

4. Measured with the half-bridge mode switching test circuit in Figure 23.





Typical Performance - Dynamic (continued)

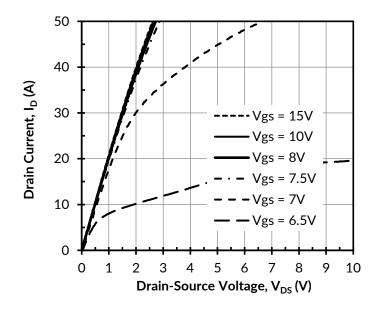
Parameter	Symbol	Test Conditions		Value		Units
Parameter	Symbol		Min	Тур	Max	Units
Turn-on delay time	t _{d(on)}	Notes 5 and 6,		12		
Rise time	t _r	$V_{DS}=400V, I_{D}=20A, Gate$ $Driver =0V to +15V,$ $Turn-on R_{G,EXT} = 1\Omega,$ $Turn-off R_{G,EXT}=5\Omega,$ inductive Load, FWD: same device with $V_{GS} = 0V \text{ and } R_{G} = 5\Omega, RC$ snubber: $R_{S}=10\Omega$ and $C_{S}=100pF,$ $T_{J}=25^{\circ}C$	V _{DS} =400V, I _D =20A, Gate 31	31		
Turn-off delay time	t _{d(off)}			42		ns
Fall time	t _f			9		
Turn-on energy including R _s energy	E _{ON}			183		
Turn-off energy including R _s energy	E _{OFF}			22		μ μ
Total switching energy	E _{TOTAL}			205		
Snubber R _s energy during turn-on	E _{RS_ON}			0.95		
Snubber R _s energy during turn-off	E _{RS_OFF}			1.41		
Turn-on delay time	t _{d(on)}	Notes 5 and 6,		12		
Rise time	t _r	V _{DS} =400V, I _D =20A, Gate		34		
Turn-off delay time	t _{d(off)}	Driver =0V to +15V,		47		ns
Fall time	t _f	Turn-on $R_{G,EXT} = 1\Omega$, Turn-off $R_{G,EXT}=5\Omega$, inductive Load, FWD: same device with		10		
Turn-on energy including R _s energy	E _{ON}			207		
Turn-off energy including R _s energy	E _{OFF}			25]
Total switching energy	E _{TOTAL}	$-$ V _{GS} = 0V and R _G = 5 Ω , RC $-$ snubber: R _S =10 Ω and		232		μJ
Snubber R _s energy during turn-on	E _{RS_ON}	C _s =100pF,		0.91		
Snubber R _s energy during turn-off	E _{RS_OFF}	T _J =150°C		1.42		1

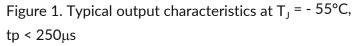
5. Measured with the chopper mode switching test circuit in Figure 24.

6. In this table, the switching energies (turn-on energy, turn-off energy and total energy) presented include the device RC snubber energy losses.



Typical Performance Diagrams





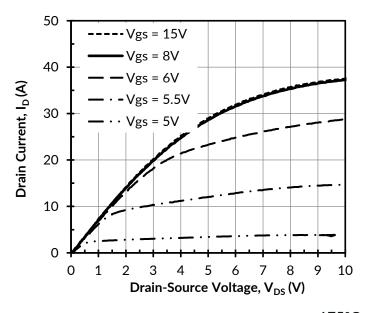
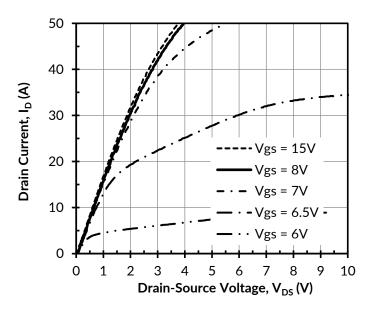


Figure 3. Typical output characteristics at $T_{\rm J}$ = 175°C, tp < 250 μs



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Figure 2. Typical output characteristics at $T_J = 25^{\circ}$ C, tp < 250µs

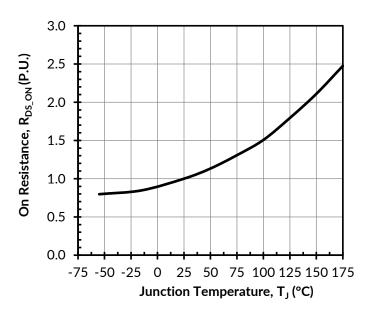


Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_{D} = 20A

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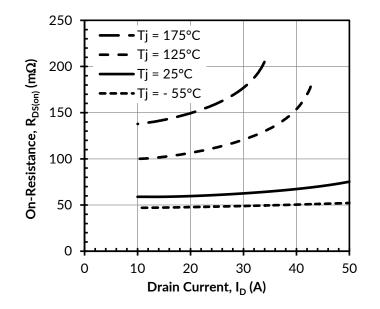
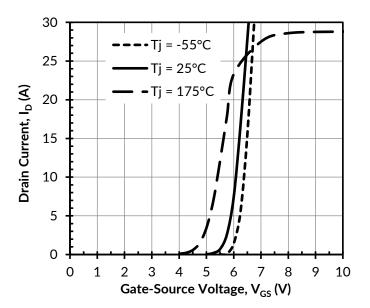


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V



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Figure 6. Typical transfer characteristics at V_{DS} = 5V

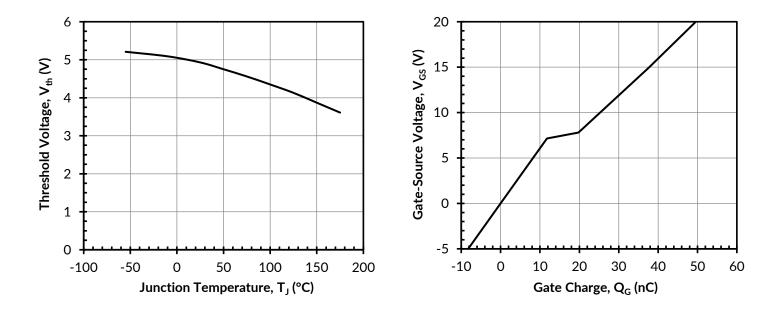
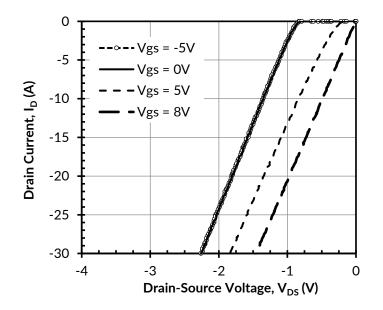


Figure 7. Threshold voltage vs. junction temperature at Figure 8. Typical gate charge at I_D = 20A V_{DS} = 5V and I_{D} = 10mA





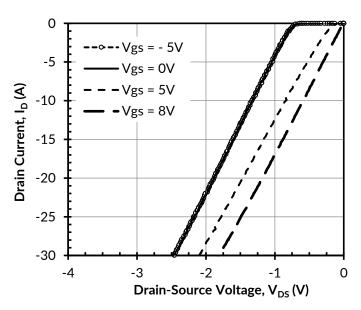


Figure 9. 3rd quadrant characteristics at $T_J = -55^{\circ}C$

Figure 10. 3rd quadrant characteristics at $T_J = 25^{\circ}C$

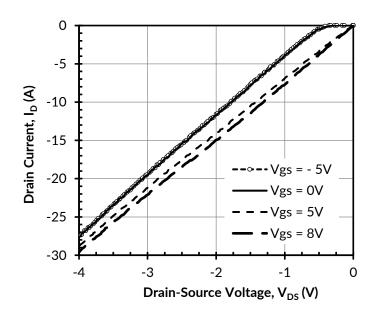


Figure 11. 3rd quadrant characteristics at $T_J = 175^{\circ}C$

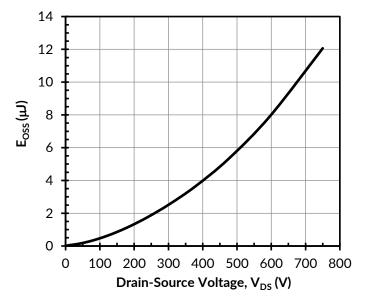


Figure 12. Typical stored energy in C_{OSS} at V_{GS} = 0V

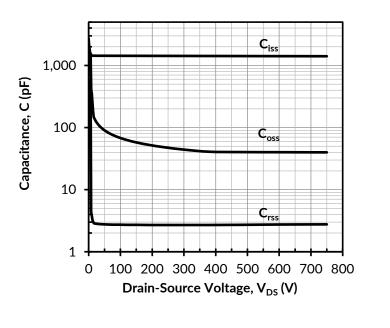
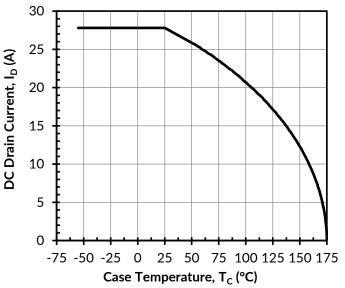


Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V



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Figure 14. DC drain current derating

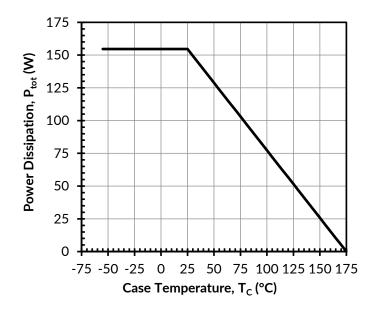


Figure 15. Total power dissipation

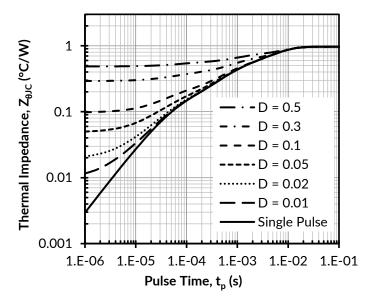


Figure 16. Maximum transient thermal impedance

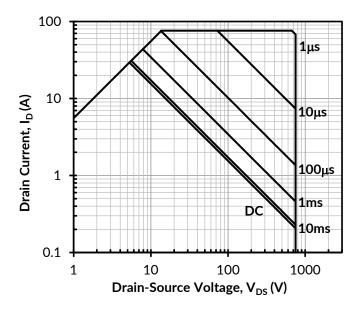


Figure 17. Safe operation area at $T_C = 25^{\circ}C$, D = 0, Parameter t_p

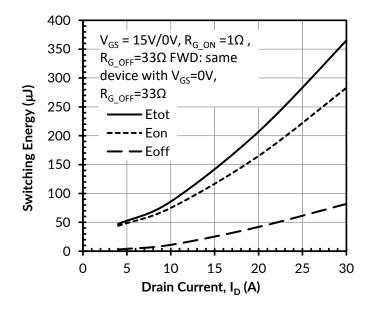
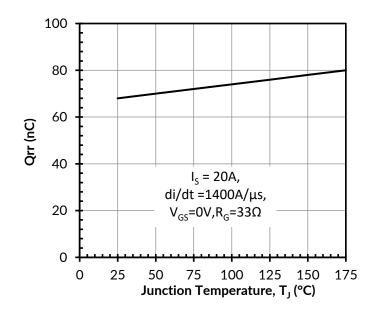


Figure 19. Clamped inductive switching energy vs. drain current at V_{DS} = 400V and T_J = 25°C



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Figure 18. Reverse recovery charge Qrr vs. junction temperature at V_{DS} = 400V

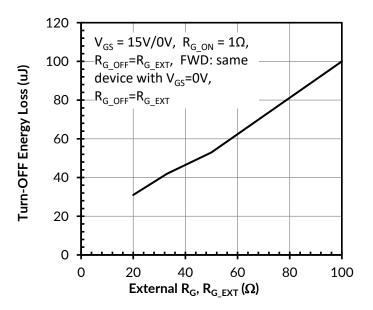


Figure 20. Clamped inductive switching turn-off energy vs. R_{G,EXT_OFF}

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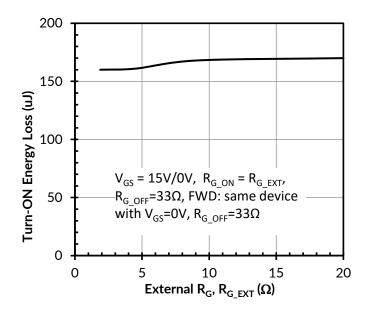


Figure 21. Clamped inductive switching turn-off energy vs. R_{G,EXT_ON}

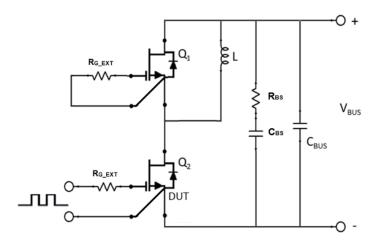
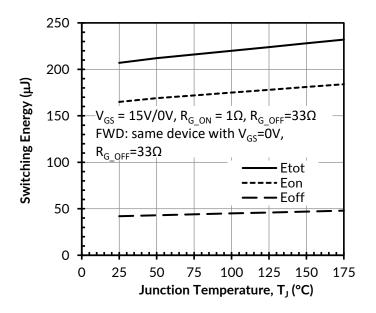


Figure 23. Schematic of the half-bridge mode switching test circuit. Note, a bus RC snubber (R_{BS} = 2.5 Ω , C_{BS} =100nF) is used to reduce the power loop high frequency oscillations.



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Figure 22. Clamped inductive switching energy vs. junction temperature at V_{DS} = 400V and I_D = 20A

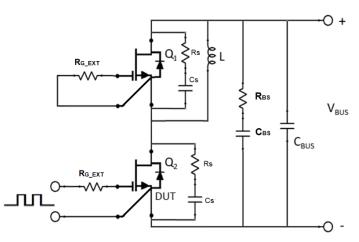
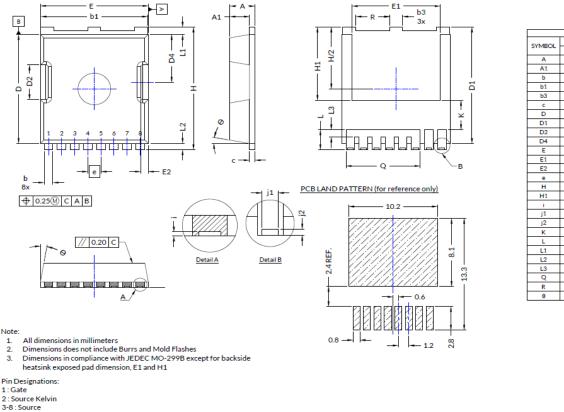


Figure 24. Schematic of the half-bridge mode switching test circuit with device RC snubbers (R_s =10 Ω , C_s = 100pF) and a bus RC snubber (R_{BS} = 2.5 Ω , C_{BS} =100nF).





Package Outlines



	TC)-LL	
SYMBOL		Value	
STINDOL	Min	Nom	Max
Α	2.15	2.30	2.45
A1		1.80 REF	
b	0.70	0.80	0.90
b1	9.65	9.80	9.95
b3	1.10	1.20	1.30
c	0.40	0.50	0.60
D	10.18	10.38	10.58
D1	10.98	11.08	11.18
D2	3.15	3.30	3.45
D4	4.40	4.55	4.70
E	9.70	9.90	10.10
E1	7.95	8.10	8.25
E2	0.60	0.70	0.80
е		1.20 BSC	
н	11.48	11.68	11.88
H1	6.80	6.95	7.10
i		0.10 REF	
j1		0.46 REF	
j2		0.20 REF	
к		2.80 REF	
L	1.40	1.90	2.10
L1	0.50	0.70	0.90
L2	0.48	0.60	0.72
L3	0.30	0.70	0.80
Q		6.80 REF	
R	3.00	3.10	3.20
8		10°	

Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see https://www.qorvo.com/design-hub.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at https://www.qorvo.com/design-hub.



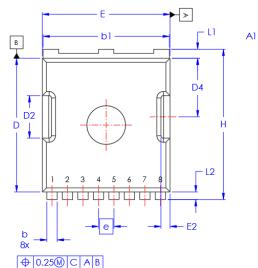


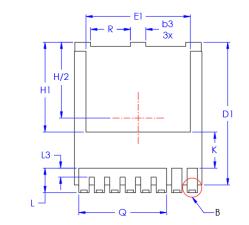
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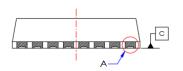
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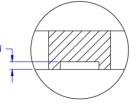


PACKAGE OUTLINE

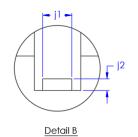








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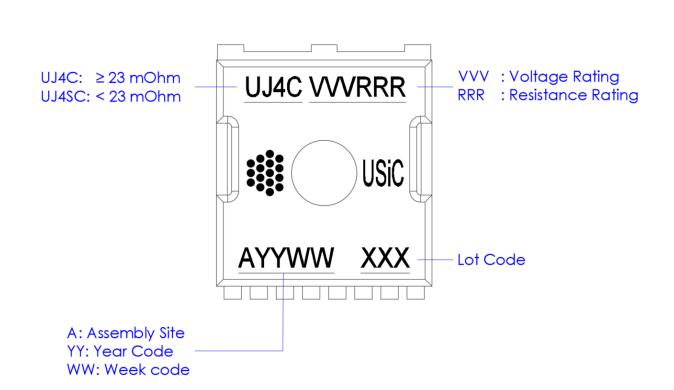
<u>Detail A</u>

- Note: 1. All dimensions in millimeters
 - 2. Dimensions does not include Burrs and Mold Flashes

TO-LL					
SYMBOL	Value				
	Min	Max			
A	2.15	2.45			
Al	1.80	REF			
b	0.65	0.90			
bl	9.65	9.95			
b3	1.10	1.30			
С	0.40	0.60			
D	10.18	10.58			
DI	10.88	11.28			
D2	3.15	3.45			
D4	4.40	4.70			
E	9.70	10.10			
E1	7.95	8.25			
E2	0.60	0.80			
е	1.20 BSC				
Н	11.48	11.88			
H1	6.80	7.10			
i	0.10	REF			
j1	0.46	REF			
j2	0.20	REF			
K	2.80	REF			
L	1.40	2.10			
L1	0.50	0.90			
L2	0.48	0.72			
L3	0.30	0.80			
Q	6.80	REF			
R	3.00	3.20			



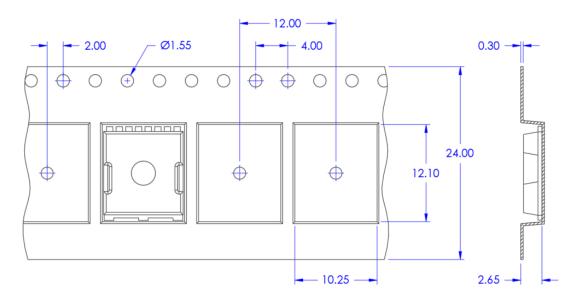
PART MARKING



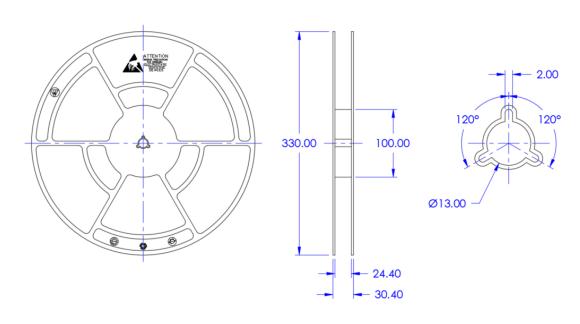


PACKING TYPE

Carrier Tape



<u>Reel</u>



All dimensions in millimeters Quantity per Reel: 2000 units



TOLL PACKAGE OUTLINE, PART MARKING, TAPE AND REEL SPECIFICATION	Page 4 of 4
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REVISION HISTORY

Revision	Create Date (mm/dd/yyyy)	Description of Change	Initiator of Change
A	10/13/2023	Initial Production Release	Glenn Galang
В	01/31/2024	Corrected device orientation inside carrier tape pocket (Page 3)	Glenn Galang

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